- Unbuffered Outputs
- Package Options Include Plastic Small-Outline (D) and Ceramic Flat (W)
  Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J)
  300-mil DIPs

#### description

These devices contain six independent inverters. They perform the Boolean function  $Y = \overline{A}$  in positive logic.

The SN54HCU04 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74HCU04 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each inverter)

INPUT A	OUTPUT Y
Н	L
L	Н

#### logic symbol†

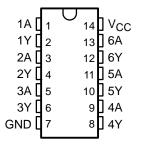
10 1	1 2 1Y
1A 3	4
2A 3 5	6 2Y
3A 9	8 3Y
4A 11	
5A 13 13	12 5Y

 $<sup>\</sup>ensuremath{^{\dagger}}$  This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

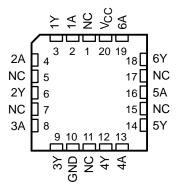
Pin numbers shown are for the D, J, N, and W packages.

### ages.

#### SN54HCU04 . . . J OR W PACKAGE SN74HCU04 . . . D OR N PACKAGE (TOP VIEW)



## SN54HCU04 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection



logic diagram (positive logic)





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#### absolute maximum ratings over operating free-air temperature range†

Supply voltage range, V <sub>CC</sub>	$-0.5 \text{ V to 7 V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ ) (see Note 1)	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> ) (see Note 1)	±20 mA
Continuous output current, $I_O$ ( $V_O = 0$ to $V_{CC}$ )	±25 mA
Continuous current through V <sub>CC</sub> or GND	±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2): D package	127°C/W
N package	78°C/W
Storage temperature range, T <sub>stg</sub>	–65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### recommended operating conditions

			SN	SN54HCU04 MIN NOM MAX			SN74HCU04		
			MIN				MIN NOM MAX		UNIT
VCC	Supply voltage		2	5	6	2	5	6	V
		V <sub>CC</sub> = 2 V	1.7			1.7			
$V_{IH}$	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.6			3.6			V
		V <sub>CC</sub> = 6 V	4.8			4.8			
	Low-level input voltage	V <sub>CC</sub> = 2 V	0		0.5	0		0.5	V
$V_{IL}$		V <sub>CC</sub> = 4.5 V	0		1.35	0		1.35	
		V <sub>CC</sub> = 6 V	0		1.8	0		1.8	
٧ <sub>I</sub>	Input voltage		0		VCC	0		VCC	V
٧o	Output voltage		0		VCC	0		VCC	V
		V <sub>CC</sub> = 2 V	0		1000	0		1000	
t <sub>t</sub>	Input transition (rise and fall) time	V <sub>CC</sub> = 4.5 V	0		500	0		500	ns
		V <sub>CC</sub> = 6 V	0		400	0		400	
TA	Operating free-air temperature		-55		125	-40		85	°C



<sup>2.</sup> The package thermal impedance is calculated in accordance with JESD 51, except for through-hole packages, which use a trace length of zero.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEST CONDITIONS		V	T,	Δ = 25°C	;	SN54H	CU04	SN74H	CU04	UNIT
PARAMETER	TEST CON	DITIONS	vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
			2 V	1.8			1.8		1.8		
		I <sub>OH</sub> = -20 μA	4.5 V	4			4		4		
Voн	$V_I = V_{CC}$ or GND		6 V	5.5			5.5		5.5		V
		I <sub>OH</sub> = -4 mA	4.5 V	3.98			3.7		3.84		
		$I_{OH} = -5.2 \text{ mA}$	6 V	5.48			5.2		5.34		
		I <sub>OL</sub> = 20 μA	2 V			0.2		0.2		0.2	
			4.5 V			0.5		0.5		0.5	
VOL	$V_I = V_{CC}$ or GND		6 V			0.5		0.5		0.5	V
		I <sub>OL</sub> = 4 mA	4.5 V			0.26		0.4		0.33	
		$I_{OL} = 5.2 \text{ mA}$	6 V			0.26		0.4		0.33	
lį	$V_I = V_{CC}$ or 0		6 V			±100		±1000		±1000	nA
Icc	$V_I = V_{CC}$ or 0,	I <sub>O</sub> = 0	6 V			2		40		20	μΑ
C <sub>i</sub>			2 V to 6 V		3	10		10		10	pF

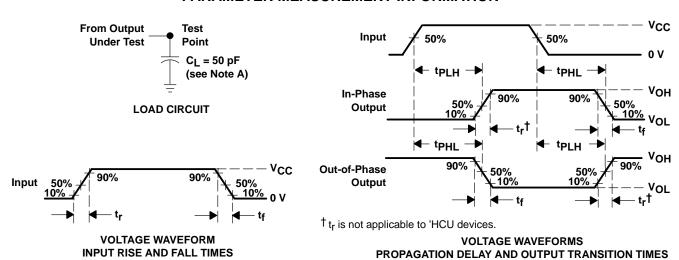
## switching characteristics over recommended operating free-air temperature range, $C_L$ = 50 pF (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO (OUTPUT)	V	T <sub>A</sub> = 25°C			SN54HCU04		SN74HCU04		UNIT
PARAMETER	(INPUT)		VCC	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
			2 V		40	80		120		100	
t <sub>pd</sub>	Α	Y	4.5 V		8	16		24		20	ns
			6 V		7	14		20		17	
			2 V		38	75		110		95	
t <sub>f</sub>		Υ	4.5 V		8	15		22		19	ns
			6 V		6	13		19		16	

### operating characteristics, $T_A = 25^{\circ}C$

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance per inverter	No load	20	pF

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A.  $C_L$  includes probe and test-fixture capacitance.

- B. Phase relationships between waveforms were chosen arbitrarily. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_r = 6 \text{ ns}$ ,  $t_f = 6 \text{ ns}$ .
- C. The outputs are measured one at a time with one input transition per measurement.
- D. tpLH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



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